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# A Low-Power CMOS Smart Temperature Sensor with a Batch-Calibrated Inaccuracy of $\pm 0.25^\circ\text{C}$ ( $\pm 3\sigma$ ) from $-70^\circ$ to $130^\circ\text{C}$

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**Abstract**—In this paper, a low-power CMOS smart temperature sensor is presented. The temperature information extracted using substrate PNP transistors is digitized with a resolution of  $0.03^\circ\text{C}$  using a precision switched-capacitor (SC) incremental  $\Delta\Sigma$  A/D converter. After batch calibration, an inaccuracy of  $\pm 0.25^\circ\text{C}$  ( $\pm 3\sigma$ ) from  $-70^\circ\text{C}$  to  $130^\circ\text{C}$  is obtained. This represents a two-fold improvement compared to the state-of-the-art. After individual calibration at room temperature, an inaccuracy better than  $\pm 0.1^\circ\text{C}$  over the military temperature range is obtained, which is in-line with the state-of-the-art. This performance is achieved at a power consumption of  $65\mu\text{W}$  during a measurement time of  $100\text{ms}$ , by optimizing the power/inaccuracy trade-offs, and by employing a clock frequency proportional to absolute temperature (PTAT). The latter ensures accurate settling of the SC input stage at low temperatures, and reduces the effects of leakage currents at high temperatures.

**Index Terms**—smart temperature sensors, substrate PNP transistors, batch calibration,  $\Delta\Sigma$  A/D conversion.

## I. INTRODUCTION

SMART temperature sensors based on the substrate PNP transistors available in standard CMOS technology can achieve inaccuracies below  $\pm 0.1^\circ\text{C}$  over the military range ( $-55^\circ\text{C}$  to  $125^\circ\text{C}$ ) [1][2]. To achieve this, such sensors require individual calibration and trimming. Although efficient methods of calibration and trimming have been devised [3][4], individual calibration is still a significant cost contributor, even if it is only done at room temperature. Significant cost

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reductions can be achieved by employing batch calibration, i.e. calibrating a limited number of samples from a production batch, obtaining an estimate of their average error, and then using this information to trim the entire batch.

In this work, a CMOS temperature sensor is presented that employs batch calibration to achieve an inaccuracy of  $\pm 0.25^\circ\text{C}$  ( $\pm 3\sigma$ ) from  $-70^\circ\text{C}$  to  $130^\circ\text{C}$ , which represents a two-fold improvement on the state-of-the-art [1][5]. Moreover, the sensor achieves an inaccuracy of  $\pm 0.1^\circ\text{C}$  after individual calibration at room temperature, at par with the state-of-the-art [1], while consuming 3x less energy per measurement. While more energy-efficient temperature sensors have been reported [5][6], this is at the expense of somewhat lower accuracy.

This paper is organized as follows. Section II reviews the sensor's operating principle, and discusses the main sources of inaccuracy. Section III describes the sensor front-end at the circuit level, detailing the approach taken to achieve the combination of high accuracy and low energy consumption. Section IV addresses innovative aspects of the incremental  $\Delta\Sigma$  A/D converter, including a power-efficient implementation of its first integrator, and the use of a clock frequency proportional to absolute temperature (PTAT) to widen the sensor's temperature range. Measurement results are presented and discussed in Section V, followed by conclusions.

## II. SENSOR OPERATING PRINCIPLE

### A. Sensor Block Diagram

Fig. 1 shows a block diagram of the sensor, which consists of a front-end circuit, a  $\Delta\Sigma$  modulator and a decimation filter. In the front-end circuit, a substrate PNP transistor, either  $Q_L$  or  $Q_R$ , biased through its emitter with a current  $I_{bias}$ , generates a voltage  $V_{BE}$ , complementary to absolute temperature (CTAT), given by

$$V_{BE}(T) = \frac{kT}{q} \ln\left(\frac{I_C(T)}{I_S(T)} + 1\right) \approx \frac{kT}{q} \ln\left(\frac{I_{bias}(T)}{I_S(T)}\right), \quad (1)$$

where  $k$  is Boltzmann's constant,  $T$  the absolute temperature,  $q$  the electron charge and  $I_S$  is the transistor's saturation current. The approximation is valid for  $I_C \approx I_E = I_{bias}$  and if the ratio  $I_C/I_S \gg 1$ .

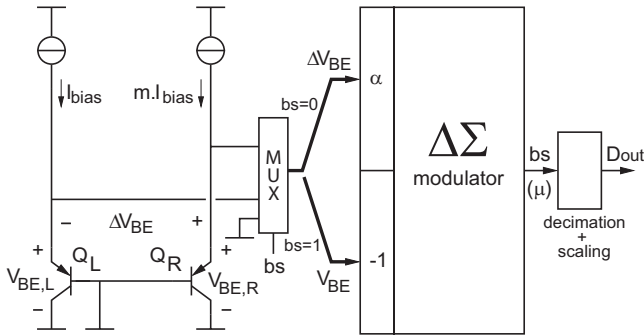


Fig. 1. Sensor block diagram. The front-end generates  $V_{BE}$  and  $\Delta V_{BE}$  that are multiplexed into the  $\Delta\Sigma$  modulator to produce a bitstream  $bs$ . A digital reading of temperature  $D_{out}$  is available after decimation/scaling.

A voltage proportional to absolute temperature (PTAT)  $\Delta V_{BE}(T) = V_{BE,R} - V_{BE,L}$ , is obtained by biasing two nominally equal PNP transistors  $Q_L$  and  $Q_R$  at a  $1:m$  current ratio, i.e.  $m = I_{bias,R}/I_{bias,L}$ . Provided the approximation in (1) is valid and mismatch errors in the bias currents and PNP transistors are negligible, this PTAT voltage, given by

$$\Delta V_{BE}(T) = \frac{kT}{q} \ln(m), \quad (2)$$

is intrinsically accurate. Ideally, it does not depend on any processing parameters [7] and, because of that, hardly suffers from process spread.

By adding to either  $V_{BE,L}$  or  $V_{BE,R}$  an amplified version of  $\Delta V_{BE}$ , i.e.  $\alpha \Delta V_{BE}$ , a first-order temperature-independent reference voltage  $V_{REF}$  is obtained

$$V_{REF} = \alpha \Delta V_{BE} + V_{BE}, \quad (3)$$

where  $\alpha$  is the scale factor required to compensate for the variation of  $V_{BE}$  with the temperature, about  $-2\text{mV}/^\circ\text{C}$ , with the variation of  $\Delta V_{BE}$  with the temperature, about  $+0.14\text{mV}/^\circ\text{C}$  for  $m=5$ . Exact values for  $\alpha$  were obtained through simulations, taking into account the actual front-end biasing and PNP emitter areas (where measured data from a previous design [1] was used to obtain an accurate simulation model).

The temperature can thus be measured ratiometrically by comparing the scaled PTAT voltage  $\alpha \Delta V_{BE}$  with the reference voltage  $V_{REF}$  [8], i.e., by evaluating the ratio  $\mu = V_{PTAT}/V_{REF}$

$$\mu = \frac{V_{PTAT}}{V_{REF}} = \frac{\alpha \Delta V_{BE}}{\alpha \Delta V_{BE} + V_{BE}} = \frac{\alpha \frac{kT}{q} \ln(m)}{\alpha \frac{kT}{q} \ln(m) + V_{BE}}, \quad (4)$$

which is also PTAT.

Whereas the front-end generates  $V_{BE}$  and  $\Delta V_{BE}$ , the  $\Delta\Sigma$  modulator generates a bitstream  $bs$ , whose average equals  $\mu$ . This is achieved through charge balancing, i.e. by properly applying, every clock cycle, either  $\alpha \Delta V_{BE}$  (when  $bs=0$ ) or  $\alpha \Delta V_{BE} - V_{REF} = -V_{BE}$  (when  $bs=1$ ) to the input of a loop-filter [1]. Because of the modulator's feedback, the average at the input of the loop filter over time is zero, and the output bitstream  $bs$  will have the desired average  $\mu$  given by (4). After decimation, the temperature reading can then be determined as

$$D_{out} = A\mu + B, \quad (5)$$

where  $A \approx 600$  and  $B \approx -273$  are the gain and offset coefficients, respectively, for a direct result in degrees Celsius.

### B. Design Approach

In order to design a low-power high-accuracy sensor, the minimum amount of power needed to minimize the various error sources must be determined. To find how each error affects the temperature measurement, the sensitivity of the measured temperature (as given in (5)) to changes in  $V_{BE}$ ,  $\Delta V_{BE}$ ,  $\alpha$  [8] and  $m$  is calculated. These sensitivities are equal to:

$$\begin{aligned} \frac{\partial V_{BE}}{\partial T} &\cong \frac{3 \text{ mV}}{^\circ\text{C}} \\ \frac{\partial \Delta V_{BE}}{\partial T} &\cong \frac{3 \text{ mV}}{^\circ\text{C}} \\ \frac{1}{\alpha} \frac{\partial \alpha}{\partial T} &\cong \frac{1}{2} \frac{^\circ\text{C}}{^\circ\text{C}} \\ \frac{\alpha}{m} \frac{\partial T}{\partial m} &\cong \frac{300 \text{ }^\circ\text{C}}{0.15} \frac{1}{^\circ\text{C}} \\ \frac{1}{m} \frac{\partial T}{\partial T} &\cong \frac{0.15}{\alpha} \frac{1}{^\circ\text{C}} \end{aligned} \quad (6)$$

Allocating a maximum error contribution of  $0.01^\circ\text{C}$  to each of the error sources, to arrive at an overall error below  $0.1^\circ\text{C}$ , a worst case variation of about  $30\mu\text{V}$  in  $V_{BE}$ ,  $2.0\mu\text{V}$  in  $\Delta V_{BE}$  (for  $\alpha=16$ ), and a maximum relative error of about  $0.0067\%$  in  $\alpha$  and  $0.01\%$  in  $m$  are found (for  $\alpha=16$ ,  $T=300\text{K}$ ). The next step is to identify the accuracy-power tradeoffs in the interface circuitry, and then determine an appropriate level of power consumption.

### C. Process Spread of $V_{BE}$

While  $\Delta V_{BE}$  is insensitive to process spread,  $V_{BE}$  suffers strongly from process spread. Statistics about  $V_{BE}$  spread can be used to estimate the initial inaccuracy (without any correction) of  $V_{BE}$ , and so of the sensor. Typically, this spread results in errors of several degrees and so the sensor must be trimmed. The success of this approach, though, will depend on the identification and reduction of the main sources of  $V_{BE}$  spread, discussed as follows.

#### 1) Spread due to the Saturation Current $I_S$

The spread of the saturation current  $I_S$  of a PNP transistor is the main cause of  $V_{BE}$  spread. In order to see how this affects  $V_{BE}$ , a deviation  $\Delta I_S$  from the nominal value  $I_S$  is introduced in the equation for  $V_{BE}$  given in (1), resulting in

$$\begin{aligned} V_{BE} &= \frac{kT}{q} \ln\left(\frac{I_{bias}}{I_S + \Delta I_S}\right) \\ &\approx V_{BE}|_{\Delta I_S=0} - \frac{kT}{q} \frac{\Delta I_S}{I_S}, \quad (\Delta I_S \ll I_S) \end{aligned} \quad (7)$$

This shows that the effect of the spread of  $I_S$  on  $V_{BE}$  is PTAT, if  $\Delta I_S/I_S$  is assumed temperature independent. Thus, the spread of  $I_S$  causes the function  $V_{BE}(T)$  to rotate around a fixed point at  $0\text{K}$ . Because this PTAT error has only one degree of freedom, it can be trimmed based on a calibration at only one temperature, e.g. room temperature [7].

However, the assumption that  $\Delta I_S/I_S$  is temperature independent is not necessarily true. Mechanical stress due to

packaging may introduce a temperature-dependency to this ratio. Luckily, vertical PNP transistors are relatively insensitive to stress [7], which is why the temperature dependency of  $\Delta I_S/I_S$  will be neglected in this work.

### 2) Spread due to the Current Gain $\beta$

Because the PNP transistors are biased via their emitters, the collector current is given by

$$I_C = \frac{\beta}{1+\beta} I_{bias} \quad (8)$$

where  $\beta$  is the forward current gain. Substituting (8) in (1) results in

$$V_{BE} = \frac{kT}{q} \ln\left(\frac{\beta}{1+\beta} \frac{I_{bias}}{I_S}\right), \quad (9)$$

which reveals that  $V_{BE}$  depends also on  $\beta$  and, because of that, is sensitive to any process-spread on  $\beta$ . To see how this affects  $V_{BE}$ , a deviation  $\Delta\beta$  from the nominal value  $\beta$  is introduced in (9), i.e.

$$\begin{aligned} V_{BE} &= \frac{kT}{q} \ln\left(\frac{\beta + \Delta\beta}{1 + (\beta + \Delta\beta)} \frac{I_{bias}}{I_S}\right) \\ &\approx V_{BE}|_{\Delta\beta=0} - \frac{kT}{q} \frac{\Delta\beta}{\beta} \frac{1}{1+\beta}, \quad (\Delta\beta \ll \beta). \end{aligned} \quad (10)$$

This shows that  $V_{BE}$  is modified by an error term that is proportional not only to  $\Delta\beta/\beta$ , but also to the factor  $1/(1+\beta)$ . Because  $\beta$  is typically highly temperature dependent, the spread in  $\beta$  will cause a non-PTAT error in  $V_{BE}$ . This adds to the PTAT error due to the spread of  $I_S$ , resulting in an overall error with more than one degree of freedom. Depending on the magnitude of  $\Delta\beta/\beta$ , a single-temperature calibration may therefore be insufficient.

Equation (10) also shows that transistors with larger  $\beta$  are less sensitive to  $\beta$  spread. Unfortunately, vertical PNP transistors in CMOS technology tend to have a small  $\beta$ . In the 0.7 $\mu$ m CMOS technology we used,  $\beta$  is approximately 22. If  $\Delta\beta/\beta$  is assumed to be about 20%, a  $V_{BE}$  variation of about  $\pm 0.25$ mV results, which translates into a temperature error of about  $\pm 0.1^\circ$ C. This shows that the effect of  $\beta$  spread in  $V_{BE}$  needs to be reduced if an inaccuracy of  $\pm 0.1^\circ$ C is to be obtained using a single-temperature calibration. This need is even more acute in deeper sub-micron CMOS technology, where much lower values of  $\beta$  are found [5][6]. A technique for making  $V_{BE}$  less sensitive to spread of  $\beta$  will be described in Section III-B.

### 3) Spread due to biasing current

The bias current,  $I_{bias}$  in (9), also affects the accuracy of  $V_{BE}$ . Generally, this bias current is derived from a bias voltage using a bias resistor. As will be discussed in the following section, if a PTAT bias voltage is used, its contribution to process spread of  $I_{bias}$  can be made negligible. The bias resistor, however, will inevitably be subject to process spread. Provided the temperature dependency of this resistor is insensitive to process variations, the effect of this on  $V_{BE}$  is

identical to that of the spread of  $I_S$ , i.e. it gives rise to a PTAT error in  $V_{BE}$ . Both errors can thus be corrected by a single PTAT trim.

## III. SENSOR FRONT-END

The sensor front-end, as shown in Fig. 2, is composed of a core that in effect generates  $V_{BE}$  and  $\Delta V_{BE}$ , as described in Section II, and of a bias circuit that generates the PTAT biasing as needed in the core.

In the core, Dynamic Element Matching (DEM) of current sources is used to provide an accurate current ratio  $m$  [9]. Every  $\Delta V_{BE}$  cycle, a different unit current source is used to bias the transistor  $Q_L$  while the  $m$  remaining ones are used to bias  $Q_R$ . By alternating the unit current source, over  $(1+m)$   $\Delta V_{BE}$  cycles, errors due to current-source mismatch are averaged out, so a more accurate 1: $m$  ratio and thus  $\Delta V_{BE}$  voltage is obtained [1]. The value of the ratio  $m$  and the bias current level, though, are subject to accuracy and power consumption constraints, as will be discussed below.

### A. Current Ratio and Bias Current

When the PNP bias current is reduced so as to lower the front-end power consumption while keeping  $(1+m)$  current sources for DEM, the approximation for  $V_{BE}$  as given in (1) is no longer accurate once the assumption of  $I_C/I_S \gg 1$  no longer applies. In this case,  $V_{BE}$  is better approximated as (assuming for now  $I_C=I_{bias}$ )

$$V_{BE} \approx V_T \ln\left(\frac{I_{bias}}{I_S} + 1\right) \quad (11)$$

which results in a  $\Delta V_{BE}$  given by

$$\Delta V_{BE} = V_T \ln\left(\frac{mI_{bias} + I_S}{I_{bias} + I_S}\right) \quad (12)$$

if the mismatch in the current sources and PNP transistors is negligible (i.e.  $I_{S,L}=I_{S,R}=I_S$ ). The result in (12) shows that, regardless of how accurately  $m$  is established, the presence of the saturation current  $I_S$  will still cause a certain error in the value of  $\Delta V_{BE}$ .

Though the magnitude of  $I_S$  can be reduced by reducing the emitter area of the PNP transistors, this is at the expense of poorer matching. The transistors also need to work in a region with neither low nor high injection effects and the region must have a constant current gain  $\beta$  [8].

The worst case relative error in the current ratio  $m$  is given by

$$\frac{\Delta m}{m} = \frac{\frac{mI_{bias} + I_{S,\max}}{I_{bias} + I_{S,\max}} - \frac{mI_{bias}}{I_{bias}}}{\frac{mI_{bias}}{I_{bias}}} \quad (13)$$

where  $I_{S,\max}$  is the largest saturation current (i.e. at the highest temperature). According to (13), for a given  $m$ , a sufficiently high  $I_{bias}$  has to be chosen to keep the error below a given level.

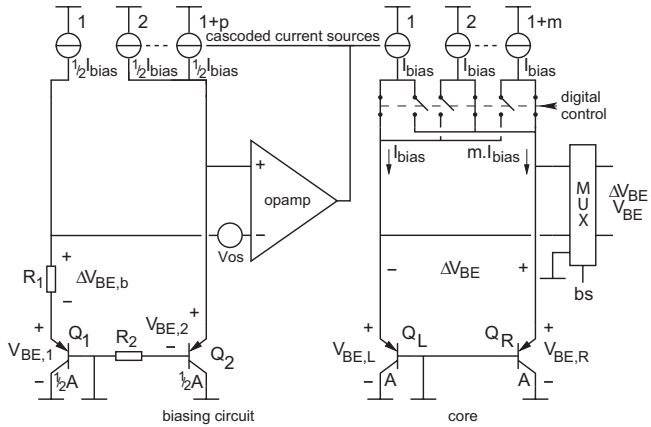


Fig. 2. Circuit diagram of the sensor front-end: biasing circuit and core (details of the bias-circuit chopping have been omitted).

However, it is more important to evaluate the error contribution due to the saturation current against the total bias current of the core, i.e.,  $I_{total}=(1+m)I_{bias}$ . Fig. 3 shows the simulated error contribution versus  $I_{total}$  for  $m=2, 5$  and  $10$ . The results show that, for a given maximum error contribution, the required bias current can be reduced by reducing the current ratio  $m$ . However, due to the resulting reduced sensitivity of  $\Delta V_{BE}$ , this comes at the expense of more stringent offset and noise requirements on the A/D converter. As a compromise,  $m$  was set to 5. In addition, in order to limit the error contribution to below  $0.02^\circ\text{C}$ ,  $I_{bias}$  was set to  $400\text{nA}$ , giving a total bias current of about  $2.3\ \mu\text{A}$ . Because the bias current is PTAT, the value of  $400\text{nA}$  (at  $T=140^\circ\text{C}$ ) translates to a nominal bias current of approximately  $250\text{nA}$  at  $T=30^\circ\text{C}$ .

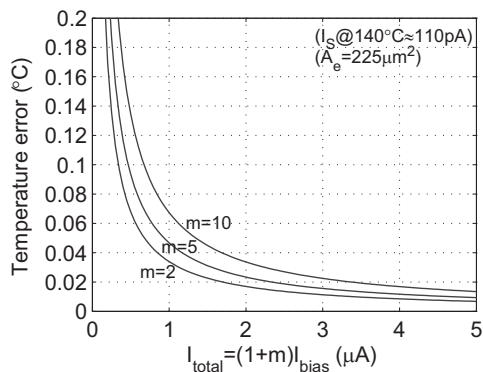


Fig. 3. Temperature error versus the total bias current  $I_{total}$ , for  $m=2, 5$  and  $10$ . Results obtained for  $I_{S,max}=110\text{pA}$  (estimated for PNPs with emitter area  $A_e=225\ \mu\text{m}^2$  at  $T=140^\circ\text{C}$  [10]).

### B. PTAT biasing- Bias Circuit

A PTAT bias current [11] was chosen to bias the two PNPs  $Q_L$  and  $Q_R$  in the core. Compared to other types of bias currents, a PTAT current can be made relatively insensitive to process spread, as it is generated from a process-insensitive PTAT voltage. Thus, only the spread of the resistor  $R_1$  (Fig. 2) causes significant spread of the currents [8]. Additionally, a PTAT current partially cancels the curvature of  $V_{BE}$  [12].

The bias circuit is built around a chopped opamp and two PNP transistors  $Q_1$  and  $Q_2$  biased at a  $1:p$  current ratio (Fig. 2).

Ignoring resistor  $R_2$  for now, the opamp forces the PTAT difference  $\Delta V_{BE,b}$  between the base-emitter voltages of these transistors to appear across resistor  $R_1$ , resulting in a PTAT unit bias current of  $\Delta V_{BE,b}/R_1$ .

Resistor  $R_2$  has been added to implement a  $\beta$ -compensation scheme [1]. The voltage drop across  $R_2$  due to the base current of  $Q_2$  makes the bias current proportional to  $(1+\beta)/\beta$  for  $R_2=R_1/p$ , so that it gives rise to a PTAT collector current when copied to the emitters of  $Q_L$  and  $Q_R$  in the core. Thus, errors in  $V_{BE}$  due to the spread of the PNP's finite current gain  $\beta$  are minimized.

As in the core,  $Q_1$  and  $Q_2$  are biased at a  $1:5$  current ratio ( $p=5$ ), but with a unit bias current of only  $125\text{nA}$  (half of that used in the core). Though a greater current ratio  $p$  would produce a greater  $\Delta V_{BE,b}$ , which is less sensitive to the opamp's offset,  $p=5$  is a better trade-off, reducing power dissipation at the expense of a small contribution to the sensor's inaccuracy (smaller than  $0.03^\circ\text{C}$ ).

Mismatch between the  $(1+p)$  current sources in the bias circuit gives rise to an error in  $\Delta V_{BE,b}$ , and hence in the PTAT bias current of the core. This, in turn, increases the spread of  $V_{BE}$  and thus the batch-calibrated inaccuracy of the sensor. Since the sensor is about an order-of-magnitude less sensitive to errors in  $V_{BE}$  than it is to errors in  $\Delta V_{BE}$ , the matching requirement for the current sources in the bias circuit is much more relaxed than that for the current sources in the core. It can be shown that matching better than  $0.15\%$  is sufficient to reduce those errors to less than  $0.01^\circ\text{C}$ . While DEM could be applied, a careful inter-digitated common-centroid layout was found to be sufficient to achieve this level of matching. The current sources of the core were included in this matched layout, to minimize the spread associated with current-source mismatch between the bias circuit and the core.

### C. Trimming Approach

In order to correct for the process spread of  $V_{BE}$ , the same  $(1+m)=6$  current sources of the core are used to digitally adjust the bias current of the PNP transistors when generating  $V_{BE}$  between  $I_{bias}$  and  $mI_{bias}$  (digital control in Fig. 2). Five of the six current sources are used to coarse trim the bias current. Because the sensor is designed to normally operate with two unit currents, there is one coarse step down and three up, which gives a near-balanced trimming capability due to the logarithmic dependency of  $V_{BE}$  on  $I_{bias}$ . To fine trim the sensor, the bitstream method [13] is used. The sixth current source is switched on and off, generating a bias current between  $0$  and  $I_{bias}$  depending on the output of a digital modulator. For a nominal bias current of  $250\text{nA}$ , an 8-bit modulator was used to obtain  $1\text{nA}$  trimming resolution.

## IV. INCREMENTAL SC $\Delta\Sigma$ ANALOG-TO-DIGITAL CONVERTER

The ratiometric measurement of  $\alpha\Delta V_{BE}$  with respect to  $V_{REF}$  has been implemented using a second-order switched-capacitor (SC) incremental  $\Delta\Sigma$  modulator. It is based on the design presented in [1], but differs from this design in two important



aspects detailed below: a more power-efficient first integrator and a new temperature-dependent clocking scheme are employed.

### A. Operating Principle

Fig. 4 shows a simplified circuit diagram of the modulator. It translates the output voltage of the front-end circuit  $V_{\Delta\Sigma}$ , which is either  $\Delta V_{BE}$  (when  $bs=0$ ) or  $-V_{BE}$  (when  $bs=1$ ), into a bitstream  $bs$  whose average value  $\mu$  equals the desired ratiometric function given by (4), as explained in Section II. A decimation filter (not shown), is used to decimate and scale this bitstream according to (5) to produce a digital output.

The modulator is operated using a two-phase non-overlapping clock. During phase  $\phi_1$ ,  $V_{\Delta\Sigma}$  is sampled on capacitors  $C_S$ , while during phase  $\phi_2$  the associated charge is transferred to the integration capacitors  $C_{int}$ . When  $bs=0$  and  $V_{\Delta\Sigma}=\Delta V_{BE}$ , all  $\alpha$  capacitors  $C_S$  are used, whereas when  $bs=1$  and  $V_{\Delta\Sigma}=-V_{BE}$ , only a single capacitor  $C_S$  is used. This implements the relative gain  $\alpha$  as needed in (3). It is worth mentioning that the value of  $\alpha=16$  for  $m=5$  establishes a reference voltage  $V_{REF}$  that is slightly dependent on the temperature, which yields further compensation of the curvature of  $V_{BE}$  [12], in addition to the PTAT biasing. Because of the modulator's feedback, the average charge integrated over time is zero, i.e.

$$(1-\mu)\alpha C_S \Delta V_{BE} + \mu C_S (-V_{BE}) = 0 \quad (14)$$

which results, when solved for  $\mu$ , in the expression given by (4).

The size of the sampling capacitors ( $C_S=2.5\text{pF}$ ) was a trade-off between settling time, on one hand, and  $kT/C$  noise and most importantly charge injection error on the other.

To ensure that the modulator does not introduce any significant errors, several precision techniques are applied [1][8]. Offset errors are reduced below  $2\mu\text{V}$  (which corresponds to  $0.01^\circ\text{C}$ ) by means of a combination of correlated double sampling (CDS) [14] in the first integrator and system-level chopping. Errors in the factor  $\alpha$  due to capacitor mismatch are mitigated by applying dynamic element matching techniques, i.e. by dynamically interchanging the sampling capacitors  $C_{S_i}$ ,  $i=1,2,\dots,\alpha$  (Fig. 4), so as to average out gain errors. Because the same integration capacitor  $C_{int}$  is used, regardless of the cycle, it does not affect  $\alpha$ .

### B. Modulator Implementation – First Integrator

The first integrator is built around a fully-differential gain-boostered telescopic-cascode opamp (shown in Fig. 5). Compared to the folded-cascode topology employed in earlier work [1], a notable power saving is achieved, since the telescopic topology only needs half the supply current of the folded version for the same transconductance and maximum output swing [15]. This can be accommodated thanks to the modulator's input feed-forward topology, which minimizes the output swing [1]. Since the integrator's CDS scheme requires unity-gain feedback, the opamp was designed to operate with

identical input and output common-mode levels. Gain-boosting [16] was used to achieve a DC gain higher than a 100dB over all process corners and operating conditions, so as to ensure negligible sampling errors. Nominally, the DC gain of the first integrator is 135dB, with a GBW of 200kHz. Including the boosting amplifiers, the opamp draws a total supply current of  $4.5\mu\text{A}$ .

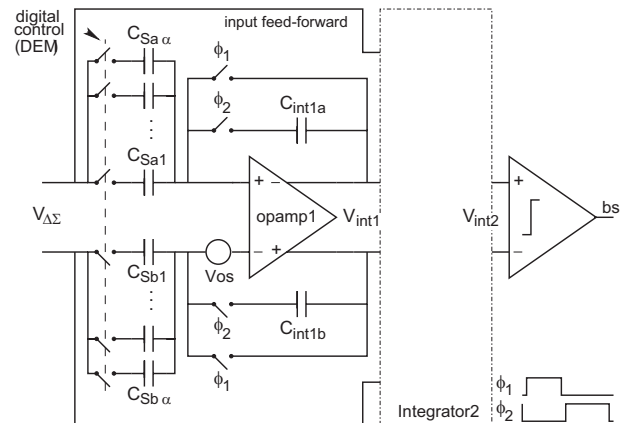


Fig. 4. Simplified circuit diagram of the second-order SC  $\Delta\Sigma$  modulator.

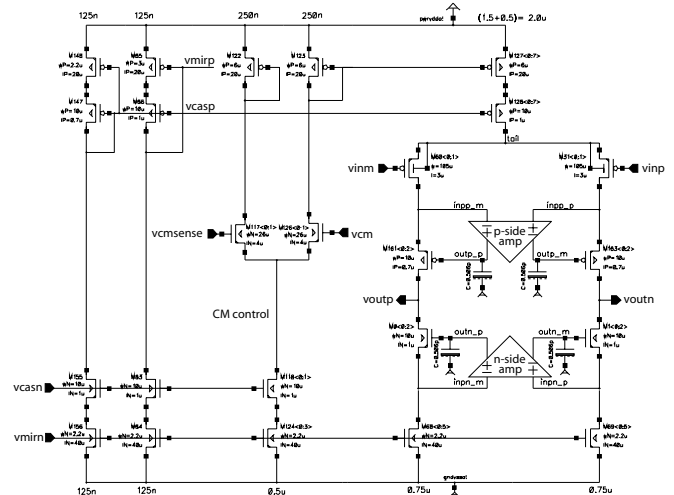


Fig. 5. Schematic of the fully-differential gain-boostered telescopic-cascode opamp used to implement the first integrator (implementation details of the gain-booster amplifiers have been omitted).

### C. PTAT Clock Frequency

Because of the PTAT biasing used in the front-end, the time needed for the modulator to settle is temperature dependent. Since the modulator's sampling capacitors (capacitors  $C_S$  in Fig. 4) are indeed the front-end's output load, charging these capacitors will take longer at low temperatures. This is shown in Fig. 6, where  $V_{\Delta\Sigma}$  is the sampled voltage (either  $V_{BE}$  or  $\alpha\Delta V_{BE}$ ).

As a result, the use of a constant sampling clock frequency is sub-optimal in terms of settling time. A clock frequency optimized for accurate settling at high temperatures leads to errors at low temperatures due to incomplete settling. Conversely, a clock frequency optimized for accurate settling at low temperatures leads to a settling time that is over-

designed, and hence less power-efficient, at high temperatures. Moreover, it will lead to increased errors due to leakage at the high end of the temperature range.

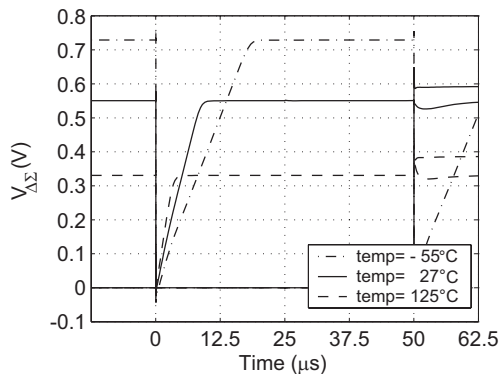


Fig. 6. Simulated slewing-time dependence on temperature (for a  $V_{BE}$  cycle, i.e.  $V_{\Delta\Sigma} = V_{BE}$ ) for a fixed clock frequency  $f = 10\text{kHz}$ .

To accommodate accurate settling at both ends of the temperature range without these issues, the sensor uses a sampling clock with a temperature-dependent frequency. At low temperatures, the frequency is lower than its nominal value, allowing more time for settling, while at high temperatures, it is higher, reducing leakage errors by shortening the sampling period.

A nominal clock frequency of 11kHz was chosen to ensure accurate settling at 30°C. To find the optimal temperature dependency of the clock frequency, it is important to account for the fact that the settling consists of a slewing phase and an exponential settling phase [17]. Taking the temperature dependence of these phases into account, an optimal frequency of about 70% of the nominal frequency is found at -55°C, and about 140% of the nominal frequency at 125°C. This leads to a frequency variation of about 1kHz/20°C, as shown in Table I. Because this temperature dependence is roughly proportional to absolute temperature, we refer to this as a PTAT clock frequency.

Temperature (°C)	From -50 to 130
Clock frequency (kHz)	8 – 17 (PTAT)

## V. MEASUREMENT RESULTS

The temperature sensor was fabricated in a standard 0.7μm CMOS process and encapsulated in a ceramic DIL package. A chip micrograph of the sensor is shown in Fig. 7. The die size is 4.5 mm<sup>2</sup>, including bondpads. The chip contains all required circuitry, except for the clock generator and decimation filter of the  $\Delta\Sigma$  ADC, which were implemented off chip for flexibility.

Measurements have been made on 20 samples from one batch. These samples were mounted, together with a precision platinum thermometer calibrated to 0.01mK, on an aluminum block that provided thermal stability. This block, in turn, was placed in a climate chamber to vary temperature.

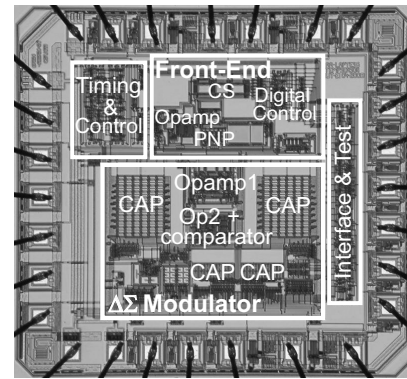


Fig. 7. Chip micrograph of the smart temperature sensor.

For all measurements presented below, the sensors were operated with a PTAT clock, as described in the previous section, and 1024 bits of their output bitstreams were decimated using a sinc<sup>2</sup> filter to calculate the bitstream average  $\mu$ . This corresponds to a nominal conversion time of 100ms. In this conversion time, the sensor achieves a resolution of 0.025°C, which was measured by taking the standard deviation of successive readings at room temperature.

### A. Batch-Calibrated Results

Four arbitrary sensors were initially characterized to perform the batch calibration. The bitstream average  $\mu$  of each of these sensors was recorded over the operating temperature range. The coefficients  $A$  and  $B$  in (5) were then chosen such that the average measurement error of the four samples with respect to the platinum thermometer was minimized. The coefficients  $A=578.68$  and  $B=-278.56$  thus found correct for the average offset and gain errors of the four samples, which is assumed to be a reasonable estimate of the average of the batch.

Fig. 8 shows the temperature error for all 20 samples when these same coefficients are used to translate their measured bitstream averages to temperature readings. To obtain these results, third-order curvature compensation was applied to remove the residual systematic non-linearity. This was less than 0.1°C and was compensated for by adding a non-linear correction term, obtained from a look-up table, after decimation. At the high-end of the temperature range, the additive correction term also helps to reduce systematic errors due to leakage. Thus, an inaccuracy below  $\pm 0.25^\circ\text{C}$  ( $\pm 3\sigma$ ) was obtained from -70°C to 130°C, which is twice as good as the best batch-calibrated inaccuracy reported to date (refer to Table II). This level of accuracy is maintained for a supply-voltage range from 2.5V to 3.3V, while the inaccuracy increases to  $\pm 0.3^\circ\text{C}$  for a supply voltage of 5.5V.

### B. Individually-Calibrated Results

Fig. 9 shows the temperature error after trimming based on an individual calibration at 30°C. After correction for systematic non-linearity, a temperature error of  $\pm 0.1^\circ\text{C}$  ( $\pm 3\sigma$ ) from -55°C to 125°C is achieved, which matches the state-of-art [1], but at 3 times less power consumption.

In addition, Fig. 10 presents the same result as that of Fig. 9, but without correction for systematic non-linearity. As expected, the inaccuracy of  $\pm 0.15^\circ\text{C}$  for the same temperature range is slightly worse, but it shows the well-defined and systematic curvature behavior of the samples, as well as a small systematic error due to leakage at  $125^\circ\text{C}$ .

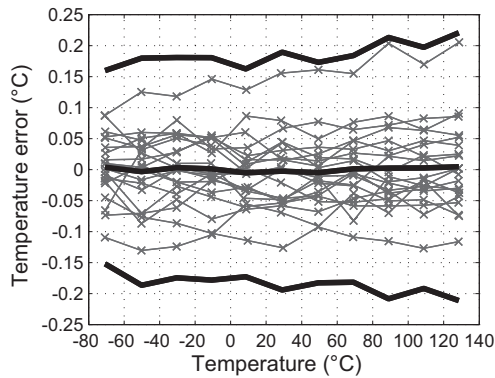


Fig. 8. Measured temperature error after batch calibration (20 samples with average and  $\pm 3\sigma$  limits).

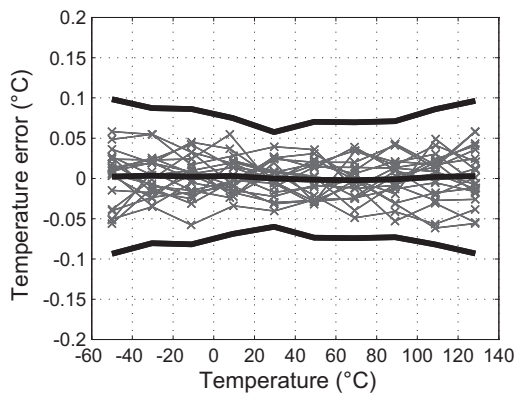


Fig. 9. Measured temperature error after trimming based on an individual calibration at  $30^\circ\text{C}$  (20 samples with average and  $\pm 3\sigma$  limits).

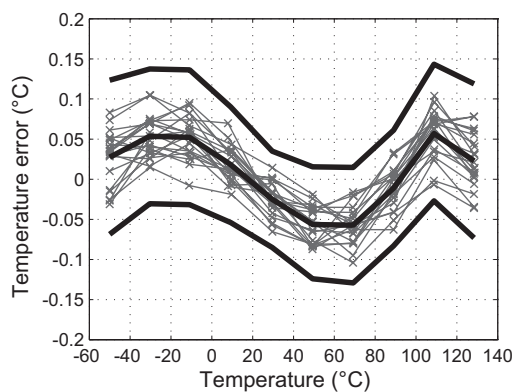


Fig. 10. Measured temperature error without compensation for systematic non-linearity and leakage, after trimming based on an individual calibration at  $30^\circ\text{C}$  (20 samples with average and  $\pm 3\sigma$  limits).

### C. PTAT Clock Frequency versus Fixed Clock Frequency

Measurement results comparing the sensor performance using the PTAT clock frequency (center frequency  $f_{nom}=11\text{kHz}$ ) and a fixed ( $11\text{kHz}$ ) clock frequency are shown in

Fig. 11. As expected, the PTAT clock leads to the same performance as a fixed clock in the middle of the temperature range, but it delivers superior performance at the temperature extremes: up to 50% less batch-calibrated inaccuracy at  $-55^\circ\text{C}$ .

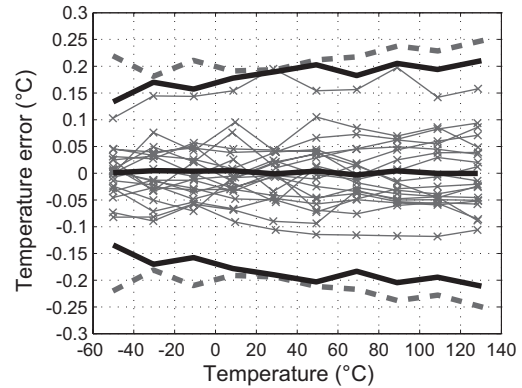


Fig. 11. Measured temperature error using a PTAT clock frequency (nominal frequency  $f_{nom} = 11\text{kHz}$ ) and fixed clock frequency ( $f = 11\text{kHz}$ , dashed lines) (20 samples with average and  $\pm 3\sigma$  limits).

### D. Measurement at $150^\circ\text{C}$

The 20 samples were also tested up to  $150^\circ\text{C}$ . At these temperatures, the PTAT clock frequency cannot compensate completely for the exponential rise in the leakage current. Therefore, clock frequencies higher than that defined by a PTAT characteristic were tested. The measured temperature errors, shown in Fig. 12, show a systematic non-linearity varying according to the clock frequency. For instance, at  $150^\circ\text{C}$ , a systematic error (on average) of  $-0.9^\circ\text{C}$ ,  $-0.5^\circ\text{C}$  and  $0^\circ\text{C}$  is observed for clock frequencies of  $20\text{kHz}$ ,  $25\text{kHz}$  and  $35\text{kHz}$ , respectively. Because of the very systematic error behavior, the same non-linearity correction used to handle the third-order curvature can be used to compensate for leakage at  $150^\circ\text{C}$ . As shown, this extends the sensor's operating range up to  $150^\circ\text{C}$  while maintaining  $\pm 0.25^\circ\text{C}$  inaccuracy.

### E. Benchmark

Table II summarizes the measured performance of the 20 samples and compares it with other designs.

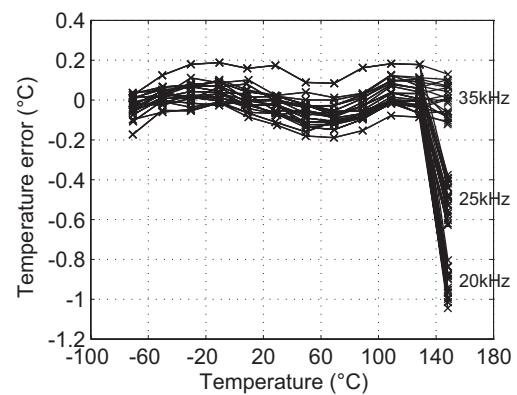


Fig. 12. Measured temperature error (extended range, up to  $150^\circ\text{C}$ ) after batch calibration, for three different clock frequencies at  $150^\circ\text{C}$ :  $20\text{kHz}$ ,  $25\text{kHz}$  and  $35\text{kHz}$  (20 samples with no third-order curvature nor leakage correction).



## VI. CONCLUSION

This paper has presented the theory, design and implementation of a CMOS smart temperature sensor based on substrate PNP transistors and an incremental SC  $\Delta\Sigma$  A/D converter. Without individual calibration, this sensor achieves an inaccuracy of  $\pm 0.25^\circ\text{C}$  ( $\pm 3\sigma$ ) from  $-70^\circ\text{C}$  to  $130^\circ\text{C}$ , twice as good as that of the best ones reported up to now, while consuming only  $62.5\mu\text{W}$  during a measurement time of 100ms. This is accomplished by optimizing the power/inaccuracy tradeoffs and by incorporating several circuit techniques, discussed throughout the paper. After an individual calibration at room temperature, the sensor achieves an inaccuracy of  $\pm 0.1^\circ\text{C}$  ( $\pm 3\sigma$ ) over the military range, which matches the state-of-the-art, while consuming 3x less energy per measurement.

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In addition to many journal and conference papers, Meijer is also author and editor of books in the field of sensor systems, published by IOP, Kluwer, Springer and Wiley.

TABLE II  
 PERFORMANCE SUMMARY AND COMPARISON. ACCURACY FOM (ENERGY  $\times$  ERROR  $\times$  %<sup>2</sup> IN nJ%<sup>2</sup>) LINE CALCULATED MOSTLY WITH DATA FROM [18].

Parameter	This work	Pertjjs [1]	Souri [6]	TMP275
Non-trimmed inaccuracy ( $\pm 3\sigma$ , batch calibrated)	$\pm 0.25^\circ\text{C}$ -70°C to 130°C	$\pm 0.5^\circ\text{C}$ -55°C to 125°C	$\pm 0.5^\circ\text{C}$ -30°C to 125°C	$\pm 1^\circ\text{C}$ max -40°C to 125°C
Trimmed inaccuracy ( $\pm 3\sigma$ , single trim at 30°C)	$\pm 0.1^\circ\text{C}$ -55°C to 125°C	$\pm 0.1^\circ\text{C}$ -55°C to 125°C	$\pm 0.2^\circ\text{C}$ -30°C to 125°C	
Resolution	0.025°C 10 conv./s	0.01°C 10 conv./s	0.015°C 10 conv./s	0.0625°C 3.3 conv./s
Supply voltage	2.5V to 5.5V	2.5V to 5.5V	1.6V to 2V	2.7V to 5.5V
Supply sensitivity (at 30°C)	0.05°C/V	0.03°C/V	0.1°C/V	-
Front-end current	5 $\mu\text{A}$	37 $\mu\text{A}$	-	-
Supply current (cont. operation)	25 $\mu\text{A}$	75 $\mu\text{A}$	4.6 $\mu\text{A}$	50 $\mu\text{A}$
Accuracy FOM (nJ% <sup>2</sup> )	76	231	49	44k
Technology	0.7 $\mu\text{m}$ , CMOS	0.7 $\mu\text{m}$ , CMOS	0.16 $\mu\text{m}$ CMOS	-
Chip area	4.5mm <sup>2</sup>	4.5mm <sup>2</sup>	0.12mm <sup>2</sup>	-
# of measured samples	20	24 samples,	19	-
# of trimming points	1-point trim	1-point trim	1-point trim	-